

**Search Notes**

Application/Control No.

10/696,299

Examiner

Y. Lee

Applicant(s)/Patent under  
Reexamination

YONEYAMA, AKIRA

Art Unit

2621

**SEARCHED**

Class	Subclass	Date	Examiner
375	240.01 240.12 240.13 240.25 240.26	6/26/2006	YL
H04N	7/12		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
375	240.26	6/26/2006	YL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR